



PostGraduate Institute
for measurement science

Training and Events September 2019



2nd September – PGI Scotland meet up

Monthly catch up of PGI students based at Strathclyde university. Come along to chat and meet other PGI students based in Scotland. Pizza and nibbles will also be provided at the event

Cost: Free

Location: Physics Common Room, John Anderson Building 8th floor, Strathclyde (16:30-19:00)

Registration: pgi@npl.co.uk

Deadline: 2nd September

3rd September - Getting the most out of conferences

This course will show you how to make the most out of such opportunities by raising your profile and confidence in attending big events. In this half day workshop, our trainer will equip you with the skills needed to engage effectively with speakers and delegates alike. Tips on asking questions, how to get noticed and prepare that all important elevator pitch, Andy help you overcome fears of public speaking and present yourself effectively.

Cost: Free

Location: NPL, Teddington or via livestream (12.30-17:00)

Registration: <https://www.eventbrite.co.uk/e/getting-the-most-out-of-conferences-tickets-68274245105>

Deadline: 27th August (First come first served)

9th September – LabVIEW Training

Week commencing the 9th September there will be a LabVIEW Training course available for students based at NPL. Laboratory Virtual Instrument Engineering Workbench is a system-design platform and development environment for a visual programming language from National Instruments. The course will show you how to get the most out of using LabVIEW. Make sure to get your managers approval before registering.

Location: NPL, Teddington

Registration: Contact keith.lines@npl.co.uk

Deadline: 2nd September

25th September – Dimensional metrology and the metre

Realisation of the metre as a laser wavelength and the use of optical interferometry to deliver a traceability path to measuring instruments. Examination of key principles for designing and operating precision dimensional equipment including use of reversal, error separation, avoiding alignment errors, error mapping and multilateration. Examination of typical measuring systems including main uncertainty budget contributions. Design and operation of traceable measuring systems for nanometrology and extension of the SI metre scale to nm and sub-nm regime using X-Ray Interferometry.

Cost: Free

Location NPL, Teddington or livestream (10:30-15:30)

Registration: internal.learning@npl.co.uk

Deadline: 17th September